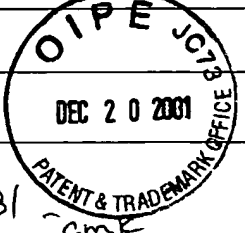


FORM PTO 1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY DOCKET NO. DEH009	SERIAL NO. 09/995,662	
	APPLICANT BATEMAN ET AL.		
	FILING DATE NOVEMBER 29, 2001	GROUP N/A 2881	

U.S. Patent Documents

Examiner Initial	Document Number	Date	Patentee/Applicant	Class	Subclass	Filing Date if Appropriate
CMK	5,572,035	11/96	FRANZEN	—	—	—
CMK	6,107,628	08/00	SMITH ET AL.	—	—	—

Foreign Patent Documents

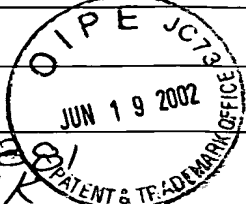
Examiner Initial	Document Number	Publication Date	Country/Agency	Class	Subclass	Translation	
						Yes	No
CMK	2,302,985	02/97	UK	—	—	✓	
CMK	WO97/49111	12/97	PCT	—	—	✓	
CMK	WO99/38185	07/99	PCT	—	—	✓	
CMK	2,281,405	03/00	CA	—	—	✓	

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CMK	Teloy et al., "Integral Cross Sections for Ion-Molecule Reactions. 'I. The Guided Beam Technique'", Chemical Physics, pp.417-427, (1974).
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CMK	Bailey et al., "Design and Implementation of a New Electrodynamical Ion Funnel", Analytical Chemistry, Vol. 72, No. 10, pp. 2247-2255, (2000).

Examiner <i>Chris Kalwoda</i>	Date Considered <i>April 9, 2003</i>
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Examiner: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; Draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	APPLICANT BATEMAN ET AL.		
	FILING DATE NOVEMBER 29, 2001	GROUP 2881 N/A CMR	

U.S. Patent Documents

Examiner Initial	Document Number	Date	Patentee/Applicant	Class	Subclass	Filing Date if Appropriate
<i>CMK</i>	5,818,055	10/98	FRANZEN	250	292	7/10/1997

Foreign Patent Documents

Examiner Initial	Document Number	Publication Date	Country/Agency	Class	Subclass	Translation	
						Yes	No
<i>CMK</i>	2,315,364	01/98	UK	—	—	✓	
<i>CMK</i>	113852	04/00	JP	—	—	✓	
<i>CMK</i>	123780	04/00	JP	—	—	✓	

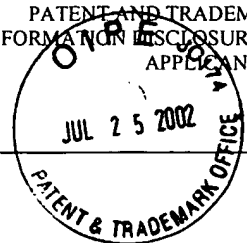
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	APPLICANT BATEMAN ET AL.	
	FILING DATE NOVEMBER 29, 2001	GROUP 2856 2881 -CMK



U.S. Patent Documents

Examiner Initial	Document Number	Date	Patentee/Applicant	Class	Subclass	Filing Date if Appropriate
CMK	2001/0035498	11/01	LI ET AL.	—	—	—

Foreign Patent Documents

Examiner Initial	Document Number	Publication Date	Country/Agency	Class	Subclass	Translation	
						Yes	No
CMK	98/06481	2/98	WO	—	—	✓	
CMK	11-307040	11/99	JP	—	—	✓	
CMK	2002-15699	1/02	JP	—	—	✓	

Other Documents (Including Author, Title, Date, Pertinent Pages, Place of Publication, Etc.)

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